

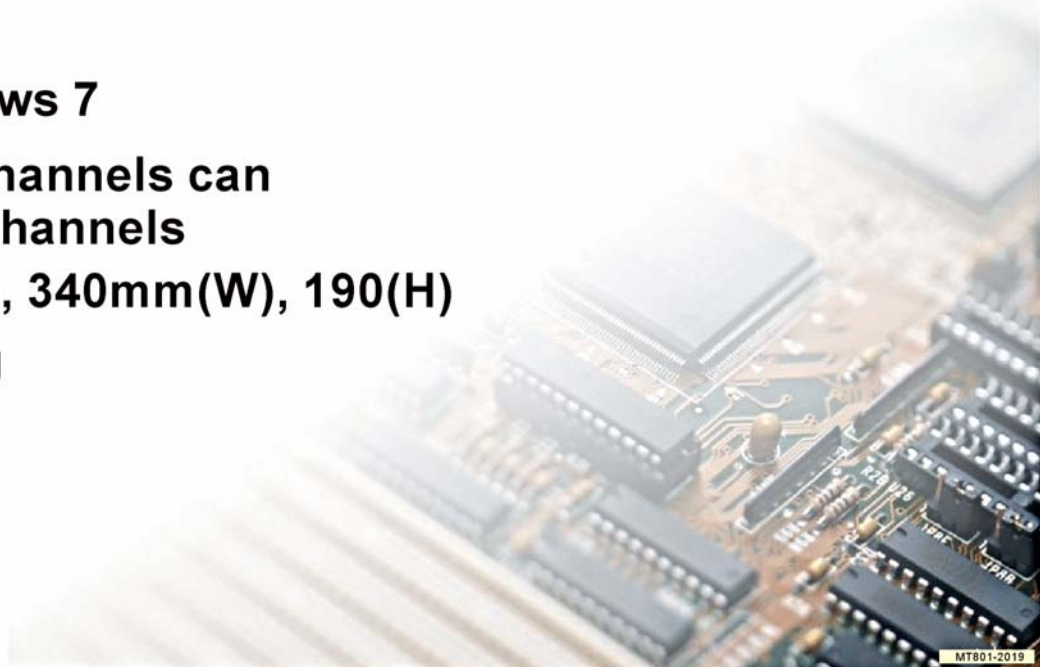
It is the smallest footprint In-Circuit Test System which could test all kind of PCBA. It is suitable for complex electronics PCBA manufacture and field service. It is a high speed all-in-one tester for electronics components, semiconductor, integrated circuit, etc, which helps factory/field service technicians easily to locate the malfunction parts. This Equipment is connected by USB cable to notebook computer.

Portable In-Circuit Tester

MT801



- Base on Windows 7
- Standard 192 channels can extend to 416 Channels
- Size: 425mm(L), 340mm(W), 190(H)
- Weight: 8~12kg



Special Testing Features:

- 3-Point test FET
- Bipolar Transistor: on/off and hFE test
- FET: on/off and V_{ds} test.
- SCR,DLAC test
- SCR Holding Current, DIAC Breakover Voltage.
- Unique ICT which combines with visual test (lighting component)Pioneer in color distinguishment software interface.

Hardware Features:

- High-speed
- High-speed performance with Reed Relay.
- Accurate
- 16 bit digital-to-analog and analog-to-digital converter offers 64K resolution for accurate measurements.
- Reliable measurement
- Direct Digital Synthesis (DDS) generates low-distortion test waveform with high frequency stability. Proprietary advanced digital filtering technology (DFT) provides an excellent signal-to-noise ratio for stable measurement.
- Capability of external camera connection
- With visual functional test board that can distinguish color by vision test.



Software Feature:

- User friendly Windows 7
- Super debug mode
- Permits fast trouble shooting. Programmable options include driving current, delay time and testing frequency.
- Waveform analyzer
- Assists in determining required delay time for accurate measurement. Patent NO: 2003201320894
- Easy to program
- Programming is easily accomplished through Auto Learn, step testing an individual editing. Tolerances can be globally edited ,guarding, skip or waiting time are edited individually.
- Functional Platform
- User friendly table form programming technique is very easy to use and support.
- Boardmap fault locator
- Automatic graphic display of fault location

Full testing features:

- Auto learn with measurement/test. methodology optimization.



- Auto guarding.
- Ten highest component failure display.
- Loop test.
- Self diagnostic function.
- Missing IC and orientation check .
- IC protective diode learning and test.
- Small capacitance values are measured by canceling the stray capacitance between the scanner and probes.
- Electrolytic capacitors reverse.
- 4-point Kelvin method to measure very small resistor.
- Provides daily of accumulated pass/fail statistics of the test results.
- A fixed voltage generate offers a fast method of charging the capacitors and saves time during testing.



Options:

- GPIB Interface
- It provides a user-friendly environment to apply dynamic functional tests. The developed Agilent and Seintek instruments to build in the system are : Universal /MultiMeter counter, Sweep/Function Generator ,Power Supply, DMM, scope ...etc.
- Bar code
- Keeps track of UUTs test status and failed records.

Specifications

- Basis channels installed: 192 test channels.
- Maximum expandable test channel: 320 test channels.
- Configuration of scanner board:
- High-speed reed relay technology with 6-wire measurement and programmable 8-wire method, 32 test channels per board.
- Guarding circuitry : 5 guarding points per step
- Signal source driving:
- DC measure:
- Programmable current source 0.1 μ A-200mA
- Programmable voltage source -10V~10V
- AC measure:
- DDS sine wave programmable frequency 1Hz-500KHz
- Open/short Testing
- 2 Programmable ranges from 1 Ω to 99 Ω
- Testing current: 1mA-10mA
- Testing speed : 500 test points per second
- Resistance
- Range: 0.1 Ω - 100M Ω
- Test speed : 2.6ms -100ms (Typical :2.6ms)
- Capacitance
- Test range: 1pF-50,000 μ F
- Test speed: DC measurement method : 8.6ms -60ms
- AC measurement method : 18ms -36ms
- ECAP polarity check Case voltage measurement
- Inductance
- Test range: 1 μ H -40H
- Test speed: 15ms -55ms
- Diode, Zener, Transistor, FET ,SCR Holding Current ,DLAC Breakover Voltage ,Photocoupler and IC missing/orientation test



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